



520.40755X00/NT0494US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Yoshimasa OHSHIMA *et al.*
Serial No. : 09/973,000
Filed : 10 October 2001
For : APPARATUS FOR DETECTING FOREIGN
PARTICLE AND DEFECT AND THE SAME METHOD
Art Unit : 2877
Examiner : Sang H. Nguyen
Confirm No. : 4791

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
POB 1450
Alexandria, Virginia 22313-1450

04 November 2003

Sir:

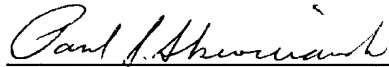
In the matter of the above-identified application, Applicant hereby submits the attached information for consideration by the Office under 37 C.F.R. §§1.97 and 1.98, and for printing on the face of any patent issuing hereon, as listed on the accompanying Form PTO-1449.

Applicant states that no item of information listed on the Form PTO-1449 was cited in a communication from a foreign Patent Office in a counterpart foreign application or known to Applicant more than three months prior to the filing of this Statement.

This Statement is being filed prior to the mailing date of a Notice of Allowance or final rejection, or any other action that closes consideration of the subject application on the merits, and is therefore timely, so no fee is required for entry and

consideration of the information submitted herein. Please charge any properly
required fees to ATS&K Deposit Account No. 01-2135 (as Order No. 520.40755X00).

Respectfully submitted,



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ATTACHMENTS:
Form PTO-1449
US 5,712,701



Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 520.40755X00	SERIAL NO. 09/793,000
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		APPLICANT Yoshimasa OHSHIMA <i>et al.</i>	
		FILING DATE 10/10/2001	GROUP 2877

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA	5,712,701	01/27/98	Clementi <i>et al.</i>			
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation/Abstract	
						Yes	No
AM							
AN							
AO							
AP							
AQ							
AR							
AS							
AT							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AU	
AV	
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AX	
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Examiner	Date Considered